

**Notice of References Cited**

Application/Control No.

10/002,024

Applicant(s)/Patent Under

Reexamination

FUTAGAWA ET AL.

Examiner

Christopher P Bruenjes

Art Unit

1772

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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